







SN65C3222E, SN75C3222E

SLLS725B - JUNE 2006 - REVISED AUGUST 2021

3-V to 5.5-V Multichannel RS-232 Line Drivers and Receivers with ±15-kV ESD Protection

1 Features

- ESD Protection for RS-232 bus pins
 - ±15-kV Human-body model (HBM)
 - ±8-kV IEC 61000-4-2, Contact discharge
 - ±15-kV IEC 61000-4-2, Air-gap discharge
- Meet or exceed the requirements of TIA/EIA-232-F and ITU v.28 standards
- Operate with 3-V to 5.5-V V_{CC} supply
- Operate up to 1000 kbit/s
- Two drivers and two receivers
- Low standby current . . . 1 µA Typ
- External capacitors . . . 4 × 0.1 µF
- Accepts 5-V Logic Input with 3.3-V supply

2 Applications

- **Industrial PCs**
- Wired Networking
- Data center and networking equipment
- **Notebooks**
- Hand-held equipment

3 Description

The SN65C3222E and SN75C3222E consist of two line drivers, two line receivers, and a dual chargepump circuit with ±15-kV ESD protection pin to pin (serial-port connection pins, including GND).

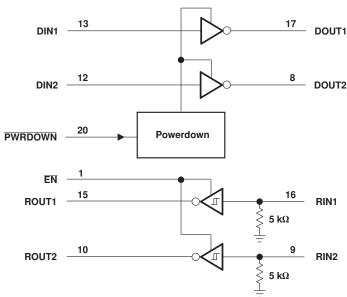
The devices meet the requirements of TIA/EIA-232-F and provide the electrical interface between an asynchronous communication controller and the serial-port connector. The charge pump and four small external capacitors allow operation from a single 3-V to 5.5-V supply. The devices operate at typical data signaling rates up to 1000 kbit/s and are improved drop-in replacements for industry-popular '3222 twodriver, two-receiver functions.

The SN65C3222E and SN75C3222E can be placed in the power-down mode by setting the power-down (PWRDOWN) input low, which draws only 1 µA from the power supply. When the devices are powered down, the receivers remain active while the drivers are placed in the high-impedance state. Also, during power down, the onboard charge pump is disabled; V+ is lowered to V_{CC}, and V- is raised toward GND. Receiver outputs also can be placed in the highimpedance state by setting enable (EN) high.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)
0.10500005	DB (SSOP) (20)	10.2 mm x 5.30 mm
SN65C3222E SN75C3222E	DW (SOIC) (20)	15.4 mm x 7.50 mm
3.1.000====	PW (TSSOP) (20)	7.80 mm v 4.40 mm

For all available packages, see the orderable addendum at the end of the data sheet.



Pin numbers are for the DB, DW, and PW packages.

Logic Diagram (Positive Logic)



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4 Revision History

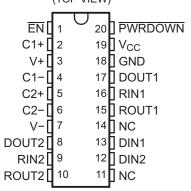
NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

CI	hanges from Revision A (July 2006) to Revision B (August 2021)	Page
•	Updated the list of Applications	1
	Deleted the Ordering Information table. Removed the RHL package from the Device Information table	
•	Added the Device Information table, the Pin Configuration and Functions, the Detailed Description secti	ion,
	the Application and Implementation section	1
•	Deleted the Package thermal impedance from the Absolute Maximum Ratings	4
•	Added the ESD Ratings table	4
•	Added the Thermal Information: SN65C3222E table	5
•	Changed the value of R _{0,JA} for PW package (previously in the Absolute Maximum Ratings table), and ac	dded
	additional thermal parameters for all packages in the <i>Thermal Information:</i> SN65C3222E table	
•	Added separate Thermal Information table for SN75C3222E	5



5 Pin Configuration and Functions

DB, DW, OR PW PACKAGE (TOP VIEW)



NC - No internal connection

Table 5-1. Pin Functions

PIN		I/O	DESCRIPTION		
NAME	NO.	1/0	DESCRIPTION		
C1+	2	_	Charge pump capacitor pin		
C1-	4	_	Charge pump capacitor pin		
C2+	5	_	Charge pump capacitor pin		
C2-	6	_	Charge pump capacitor pin		
DIN1	13	I	Driver logic input		
DIN2	12	I	Driver logic input		
DOUT1	17	0	RS-232 driver output		
DOUT2	8	0	RS-232 driver output		
EN	1	I	Receiver enable, active low		
GND	18	_	Ground		
NC	11,14	_	No internal connection		
PWRDOWN	20	I	Driver disable, active low		
RIN1	16	I	RS-232 receiver input		
RIN2	9	I	RS-232 receiver input		
ROUT1	15	0	Receiver logic output		
ROUT2	10	0	Receiver logic output		
V _{CC}	19	_	Power Supply		
V+	3	_	Charge pump capacitor pin		
V-	7	_	Charge pump capacitor pin		



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		·	MIN	MAX	UNIT
V _{CC}	Supply voltage range ⁽²⁾		-0.3	6	V
V+	Positive-output supply voltage range ⁽²⁾		-0.3	7	V
V-	Negative-output supply voltage range ⁽²⁾		0.3	-7	V
V+ – V–	Supply voltage difference ⁽²⁾			13	V
V	Input voltage range	Driver (EN, PWRDOWN)	-0.3	6	V
V _I		Receiver	-25	25	V
V	Output valtage range	Driver	-13.2	13.2	V
Vo	Output voltage range Receiver	Receiver	-0.3	V _{CC} + 0.3	V
TJ	Operating virtual junction temperature			150	°C
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

				VALUE	UNIT
V (EOD)		Human-body model (HBM), per ANSI/	All pins except RIN1, RIN2, DOUT1 and DOUT2 pins	±3,000	
	Electrostatic discharge	static ESDA/JEDEC JS-001 ⁽¹⁾ Charged device model (CDM), per ANSI/	RIN1, RIN2, DOUT1 and DOUT2 pins to GND	±15,000	V
			All pins	±1,500	

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

6.3 ESD Ratings - IEC Specifications

					VALUE	UNIT
	,	Electrostatic	IEC 61000-4-2, Contact Discharge (1)	RIN1, RIN2, DOUT1, and DOUT2 pins	±8,000	
V _(ESD)	discharge	IEC 61000-4-2, Air Discharge (1)	only	±15,000	1 V	

For the PW Package of SN65C3222E only, a minimum of 1-μF capacitor is required between V_{CC} and GND to meet the specified IEC 61000-4-2 rating

⁽²⁾ All voltages are with respect to network GND.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



6.4 Recommended Operating Conditions

See Figure 9-1 and (1)

						MAX	UNIT
	Cumplicitations		V _{CC} = 3.3 V	3	3.3	3.6	V
	Supply voltage			4.5	5	5.5	·
V _{IH}	Driver and control high-level input voltage D	DIN, EN, PWRDOWN	V _{CC} = 3.3 V	2			V
		DIN, LIN, FWINDOWN	V _{CC} = 5 V	2.4			\ \
V _{IL}	Driver and control low-level input voltage	DIN, EN, PWRDOWN				0.8	V
VI	Driver and control input voltage	DIN, EN, PWRDOWN		0		5.5	V
VI	Receiver input voltage			-25		25	V
T _A	Operating free-air temperature		SN75C3222E	0		70	°C
			SN65C3222E	-40		85	

(1) Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V.

6.5 Thermal Information: SN65C3222E

			SN65C3222E		
	THERMAL METRIC(1)	DB (SSOP)	DW (SOIC)	PW (TSSOP)	UNIT
			20 Pins	20 Pins	
R _{0JA}	Junction-to-ambient thermal resistance	70	58	94.1	°C/W
R _{θJC(top)}	Junction-to-case (bottom) thermal resistance	33.6	30.0	35.2	°C/W
R _{θJB}	Junction-to-board thermal resistance	36.4	29.6	45.5	°C/W
Ψ ЈТ	Junction-to-top characterization parameter	4.8	7.7	3.1	°C/W
Ψ JB	Junction-to-board characterization parameter	35.9	29.3	45.1	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.

6.6 Thermal Information: SN75C3222E

		DB (SSOP)	DW (SOIC)	PW (TSSOP)	
THERMAL METRIC ¹		20	20	20	UNIT
R _{θJA}	Junction-to-ambient thermal resistance	70	58	83	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	33.6	30.0	24.8	°C/W
R _{0JB}	Junction-to-board thermal resistance	36.4	29.6	39.5	°C/W
Ψ JT	Junction-to-top characterization parameter	4.8	7.7	1.1	°C/W
Ψ ЈВ	Junction-to-board characterization parameter	35.9	29.3	39.0	°C/W

6.7 Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

	PARAMETER	TEST CONDITIONS(2)	MIN TYP ⁽¹⁾	MAX	UNIT
I _I	Input leakage current (EN, PWRDOWN)		±0.01	±1	μΑ
I _{CC}	Supply current	No load, PWRDOWN at V _{CC}	0.3	1	mA
	Supply current (powered off)	No load, PWRDOWN at GND	1	10	μA

All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C. Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V.



6.8 Electrical Characteristics: Driver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

	PARAMETER	TEST COND	DITIONS	MIN	TYP (1) (3)	MAX	UNIT
V _{OH}	High-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = GND	5	5.4		V
V _{OL}	Low-level output voltage	DOUT at $R_L = 3 \text{ k}\Omega$ to GND,	DIN = V _{CC}	– 5	-5.4		V
I _{IH}	High-level input current	V _I = V _{CC}			±0.01	±1	μΑ
I _{IL}	Low-level input current	V _I at GND			±0.01	±1	μΑ
1	Short-circuit output current ⁽²⁾	V _{CC} = 3.6 V	V _O = 0 V		±35	±60	mA
los	Short-circuit output current	V _{CC} = 5.5 V	V _O – 0 V		133	IOU	IIIA
ro	Output resistance	V _{CC} , V+, and V- = 0 V,	V _O = ±2 V	300	10M		Ω
	Output leakage current	PWRDOWN = GND	V _{CC} = 3 V to 3.6 V, V _O = ±12 V			±25	
l _{oz}		tput leakage current PWRDOWN = GND	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$ $V_{O} = \pm 10 \text{ V}$			±25	μA

All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

6.9 Switching Characteristics: Driver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

	PARAMETER		TEST CONDITIONS(3)		MIN	TYP ⁽¹⁾	MAX	UNIT
			C _L = 1000 pF		250			
	Maximum data rate (See Figure 7-1)	$R_L = 3 k\Omega$, One DOUT switching	C _L = 250 pF,	V _{CC} = 3 V to 4.5 V	1000			kbit/s
	(C _L = 1000 pF,	V _{CC} = 4.5 V to 5.5 V	1000			
t _{sk(p)}	Pulse skew ⁽²⁾	C _L = 150 pF to 2500 pF,	$R_L = 3 k\Omega$ to $7 k\Omega$,	See Figure 7-2		300		ns
	Slew rate.	$R_L = 7 k\Omega$,	C _L = 150 pF to 1000 pF		8		90	
SR(tr)	transition region	$R_1 = 3 k\Omega$	C _L = 1000 pF		12		60	V/µs
	(see Figure 7-1)		C _L = 150 pF to 250 pF		24		150	

⁽¹⁾ All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

Short-circuit durations should be controlled to prevent exceeding the device absolute power dissipation ratings, and not more than one output should be shorted at a time.

Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V.

 ⁽²⁾ Pulse skew is defined as |t_{PLH} - t_{PHL}| of each channel of the same device.
 (3) Test conditions are C1-C4 = 0.1 μF at V_{CC} = 3.3 V ± 0.3 V; C1 = 0.047 μF, C2-C4 = 0.33 μF at V_{CC} = 5 V ± 0.5 V.



6.10 Electrical Characteristics: Receiver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 9-1)

	PARAMETER	TEST CONDITIONS(2)	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{OH}	High-level output voltage	I _{OH} = -1 mA	V _{CC} - 0.6	V _{CC} - 0.1		V
V _{OL}	Low-level output voltage	I _{OL} = 1.6 mA			0.4	V
.,	Positive-going input threshold voltage	V _{CC} = 3.3 V		1.5	2.4	V
V _{IT+}	Fositive-going input tilleshold voltage	V _{CC} = 5 V		1.8	2.4	V
V	Negative-going input threshold voltage	V _{CC} = 3.3 V	0.6	1.2		V
V _{IT}	Negative-going input tineshold voltage	V _{CC} = 5 V	0.8	1.5		V
V _{hys}	Input hysteresis (V _{IT+} – V _{IT-})			0.3		V
I _{OZ}	Output leakage current	EN = 1		±0.05	±10	μA
rį	Input resistance	V _I = ±3 V to ±25 V	3	5	7	kΩ

6.11 Switching Characteristics: Receiver

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

3 11 3 1 3	, , ,		
PARAMETER	TEST CONDITIONS(3)	TYP ⁽¹⁾	UNIT
Propagation delay time, low- to high-level output	C _L = 150 pF, See Figure 7-3	300	ns
Propagation delay time, high- to low-level output	C _L = 150 pF, See Figure 7-3	300	ns
Output enable time	C_L = 150 pF, R_L = 3 k Ω , See Figure 7-4	200	ns
Output disable time	C_L = 150 pF, R_L = 3 k Ω , See Figure 7-4	200	ns
Pulse skew ⁽²⁾	See Figure 7-3	300	ns
	PARAMETER Propagation delay time, low- to high-level output Propagation delay time, high- to low-level output Output enable time Output disable time	PARAMETER Test conditions(3) Propagation delay time, low- to high-level output $C_L = 150$ pF, See Figure 7-3 Propagation delay time, high- to low-level output $C_L = 150$ pF, See Figure 7-3 Output enable time $C_L = 150$ pF, $R_L = 3$ kΩ, See Figure 7-4 Output disable time $C_L = 150$ pF, $R_L = 3$ kΩ, See Figure 7-4	PARAMETERTEST CONDITIONS(3)TYP(1)Propagation delay time, low- to high-level output $C_L = 150 \text{ pF}$, See Figure 7-3300Propagation delay time, high- to low-level output $C_L = 150 \text{ pF}$, See Figure 7-3300Output enable time $C_L = 150 \text{ pF}$, $R_L = 3 \text{ k}\Omega$, See Figure 7-4200Output disable time $C_L = 150 \text{ pF}$, $R_L = 3 \text{ k}\Omega$, See Figure 7-4200

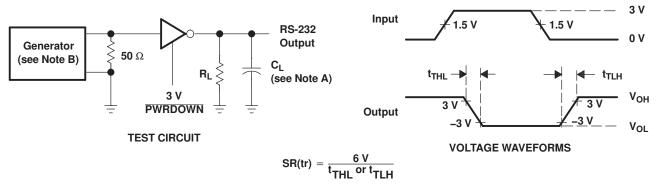
All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C.

All typical values are at V_{CC} = 3.3 V or V_{CC} = 5 V, and T_A = 25°C. Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V.

Pulse skew is defined as $|t_{PLH}-t_{PHL}|$ of each channel of the same device. Test conditions are C1–C4 = 0.1 μ F at V_{CC} = 3.3 V \pm 0.3 V; C1 = 0.047 μ F, C2–C4 = 0.33 μ F at V_{CC} = 5 V \pm 0.5 V. (3)

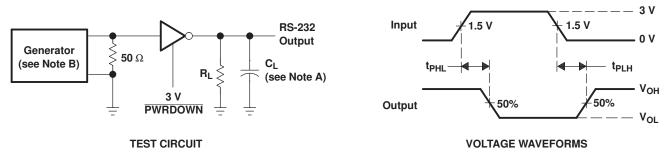


7 Parameter Measurement Information



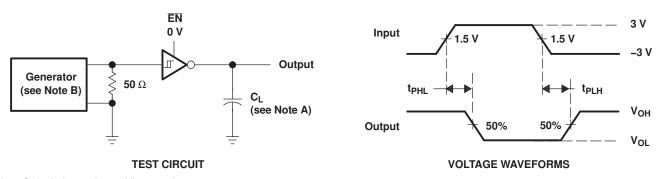
- A. C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_0 = 50 \Omega$, 50% duty cycle, $t_r \le 10$ ns, $t_f \le 10$ ns.

Figure 7-1. Driver Slew Rate



- C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: PRR = 250 kbit/s, $Z_0 = 50 \Omega$, 50% duty cycle, $t_r \le 10$ ns, $t_f \le 10$ ns.

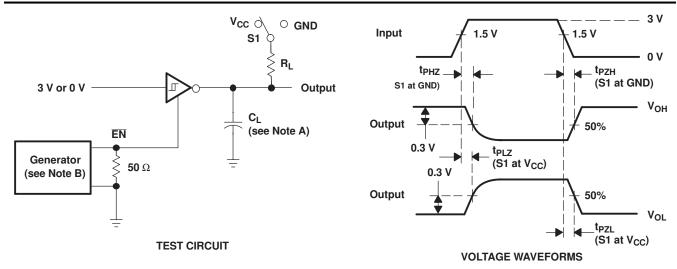
Figure 7-2. Driver Pulse Skew



- C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: Z_0 = 50 Ω , 50% duty cycle, $t_r \le 10$ ns, $t_f \le 10$ ns.

Figure 7-3. Receiver Propagation Delay Times



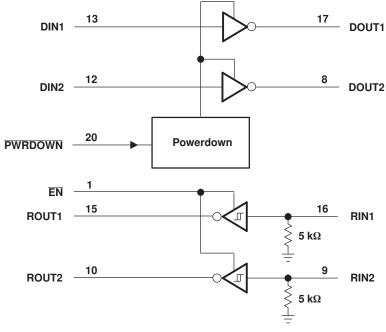


- A. C_L includes probe and jig capacitance.
- B. The pulse generator has the following characteristics: Z_0 = 50 Ω , 50% duty cycle, $t_r \le 10$ ns, $t_f \le 10$ ns.

Figure 7-4. Receiver Enable and Disable Times

8 Detailed Description

8.1 Functional Block Diagram



Pin numbers are for the DB, DW, and PW packages.

Figure 8-1. Logic Diagram (Positive Logic)

8.2 Device Functional Modes

Table 8-1. Function Tables: Each Driver

INF	PUTS ⁽¹⁾	OUTPUT
DIN	PWRDOWN	DOUT
X	L	Z
L	Н	Н
Н	Н	L

(1) H = high level, L = low level, X = irrelevant, Z = high impedance

Table 8-2. Function Table: Each Receiver

INPUTS ⁽¹⁾		OUTPUT
RIN	EN	ROUT
L	L	Н
Н	L	L
X	Н	Z
Open	L	Н

(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off),

Open = input disconnected or connected driver off



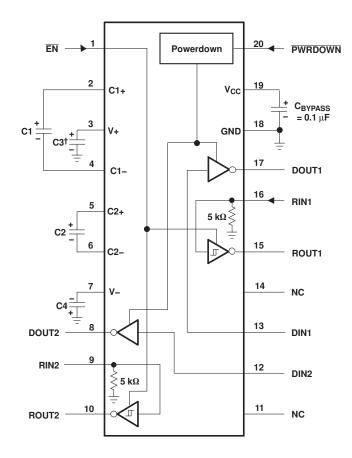
9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

9.2 Typical Application



 $^{^\}dagger$ C3 can be connected to $V_{\mbox{\footnotesize CC}}$ or GND.

NOTES: A. Resistor values shown are nominal.

V_{CC} vs CAPACITOR VALUES

V _{CC}	C1	C2, C3, and C4		
3.3 V \pm 0.3 V	0.1 μ F	0.1 μ F		
5 V \pm 0.5 V	0.047 μ F	0.33 μ F		
3 V to 5.5 V	0.1 μ F	0.47 μ F		

Figure 9-1. Typical Operating Circuit and Capacitor Values

B. NC - No internal connection

C. Nonpolarized ceramic capacitors are acceptable. If polarized tantalum or electrolytic capacitors are used, they should be connected as shown.

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

10.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com 14-Jun-2023

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
SN65C3222EDB	LIFEBUY	SSOP	DB	20	70	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MU222E	
SN65C3222EDBR	LIFEBUY	SSOP	DB	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MU222E	
SN65C3222EDW	LIFEBUY	SOIC	DW	20	25	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65C3222E	
SN65C3222EDWR	LIFEBUY	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	65C3222E	
SN65C3222EPWR	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	MU222E	Samples
SN75C3222EPW	LIFEBUY	TSSOP	PW	20	70	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	MY222E	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

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continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

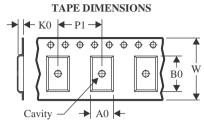
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

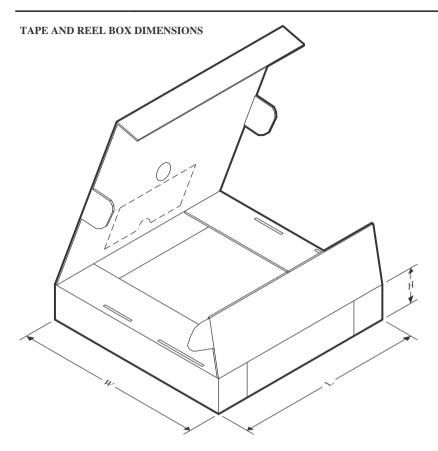


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65C3222EDBR	SSOP	DB	20	2000	330.0	16.4	8.2	7.5	2.5	12.0	16.0	Q1
SN65C3222EDWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
SN65C3222EPWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1
SN65C3222EPWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.0	1.4	8.0	16.0	Q1



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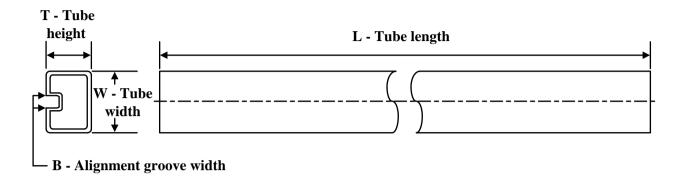
*All dimensions are nominal

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Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65C3222EDBR	SSOP	DB	20	2000	356.0	356.0	35.0
SN65C3222EDWR	SOIC	DW	20	2000	367.0	367.0	45.0
SN65C3222EPWR	TSSOP	PW	20	2000	356.0	356.0	35.0
SN65C3222EPWR	TSSOP	PW	20	2000	356.0	356.0	35.0

PACKAGE MATERIALS INFORMATION

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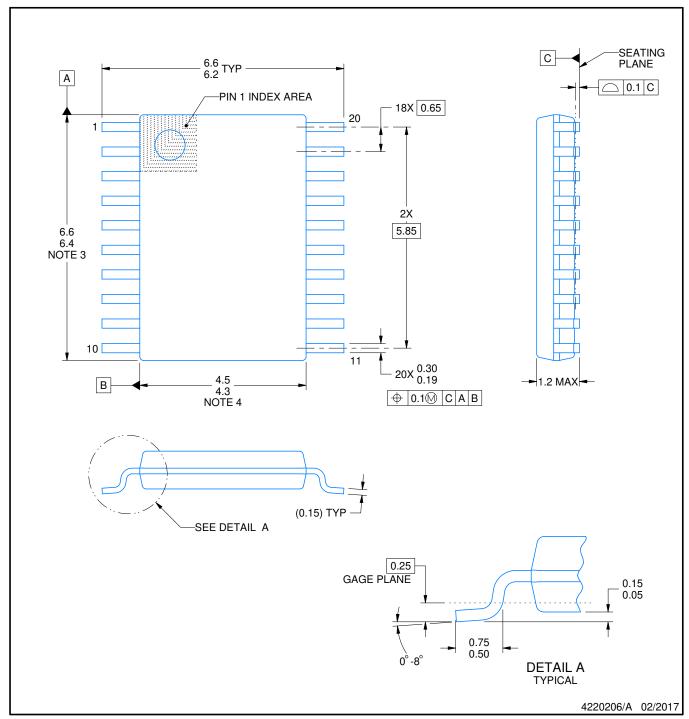
TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
SN65C3222EDB	DB	SSOP	20	70	530	10.5	4000	4.1
SN65C3222EDW	DW	SOIC	20	25	507	12.83	5080	6.6
SN75C3222EPW	PW	TSSOP	20	70	530	10.2	3600	3.5





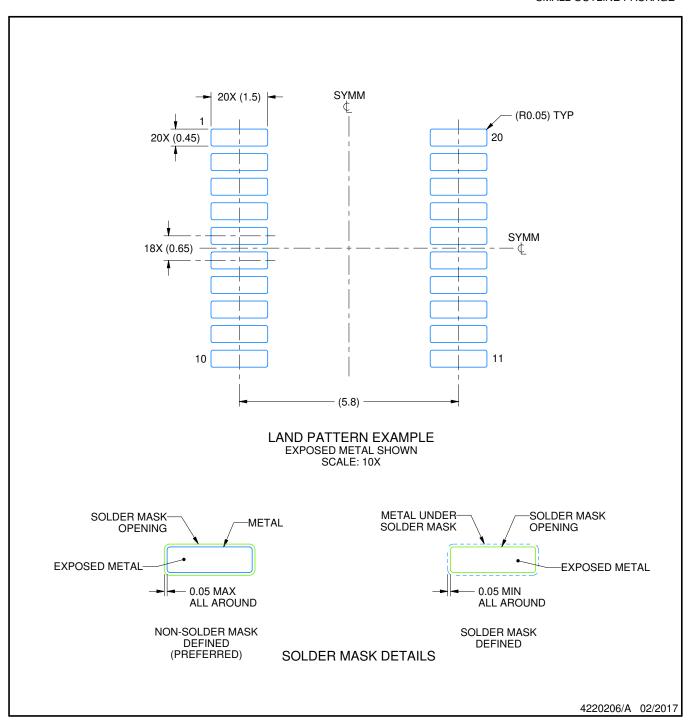
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



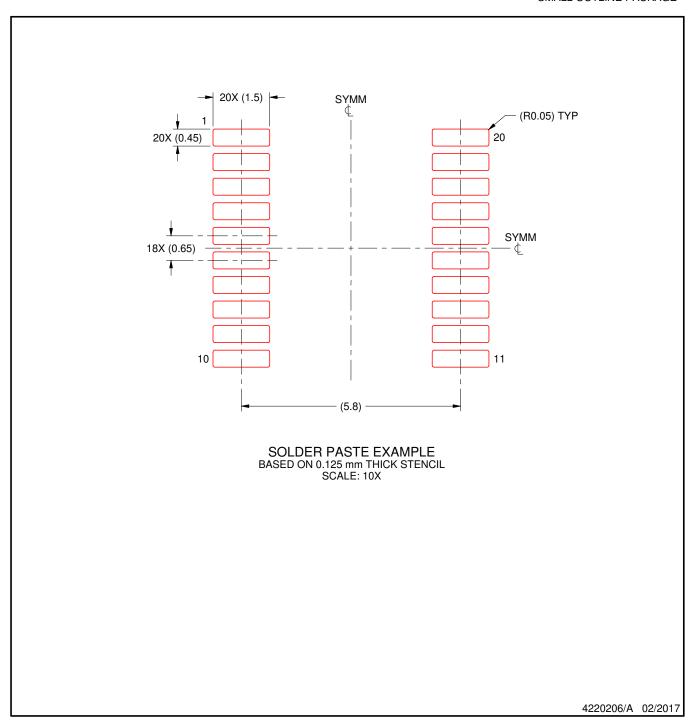


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



PW (R-PDSO-G20)

PLASTIC SMALL OUTLINE

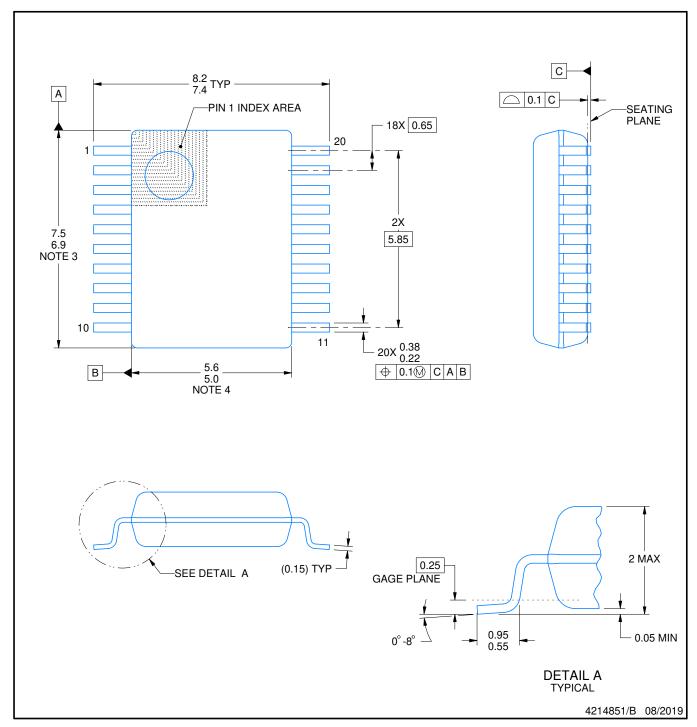


NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
 C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.







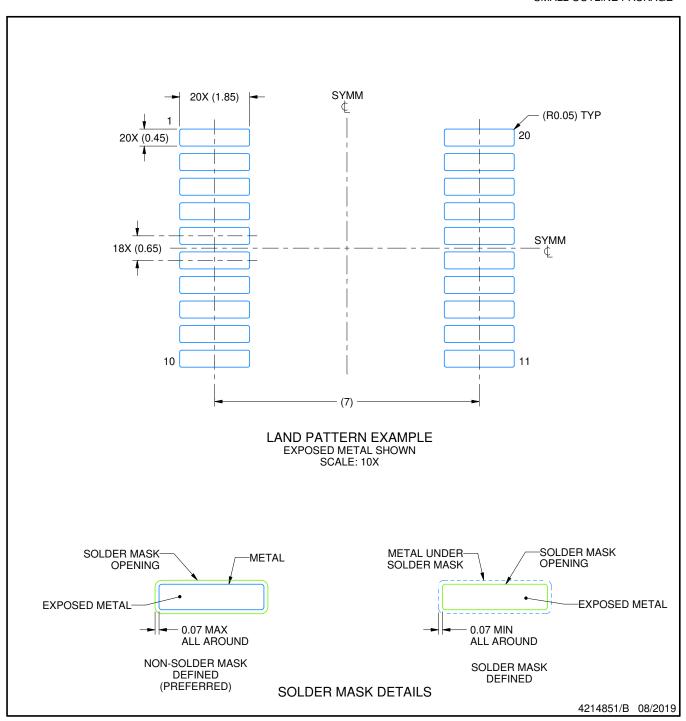
NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-150.



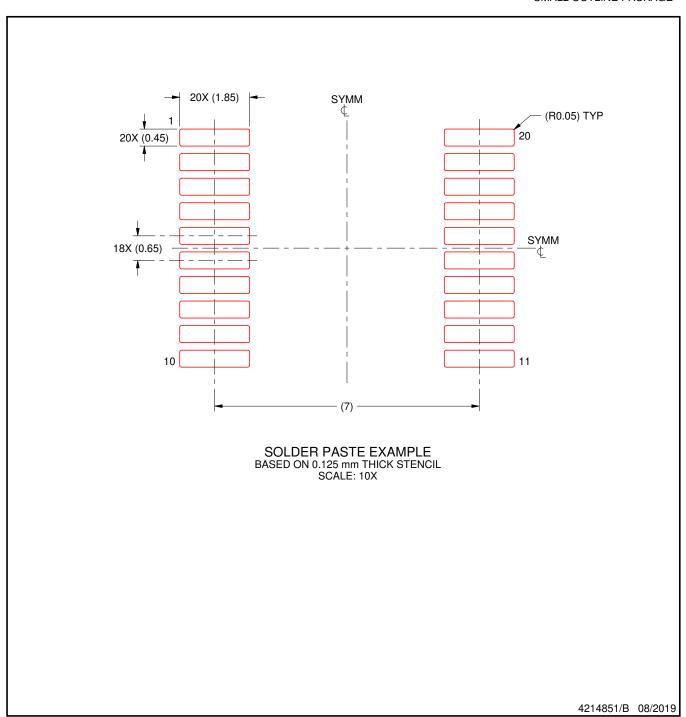


NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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